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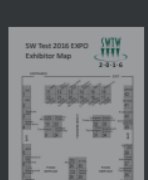
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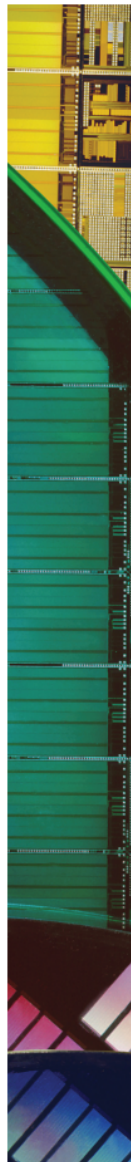


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SW Test Workshop

Semiconductor Wafer Test Workshop

Tuesday, June 7, 2016

PROCEEDINGS

June 5-8, 2016
Rancho Bernardo Inn, San Diego, CA

www.swtest.org

Chairman's Welcome to SW Test Workshop
Wafer Test Technology

On behalf of the SW Test Executive Team, Program Committee, and Committee Members, it is my great pleasure to welcome you to San Diego and the 26th Annual SW Test Workshop held at the Rancho Bernardo Inn. This is the premier international workshop that focuses on all the aspects of microelectronic wafer and die level testing. Over the past 26-years, we have had over 8000 workshop attendees, many generous corporate sponsors, and more than 500 exhibitors in attendance.

For SW Test 2016, the SW Test Program Committee had a very difficult task of selecting 28 submissions for podium presentation during 9-technical sessions. Attendees will find a diverse technical program that covers many of real-world challenges. We have chosen excellent work from suppliers and end-users with innovative approaches for solving probe challenges associated with the next generation devices and process. Industry leaders in manufacturing detail improved fabrication processes and materials development that facilitate